

OIP  
OCT 0 9  
PATENT & TRADE

## SEARCHED

Class	Sub.	Date	Exmr.
270	281 282 397	06/28/03	BES

## INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

WEST (ear)	Date	Exmr.
(microscopy or enhance) near 3 (dynamic or sensitive) near 2 range and (mass spectrometry) + directed lens + defocus + switch near 4 (low/high sensitivity)	06/28/03	BES